			AND DESCRIPTION OF THE PARTY OF		Management and a second				
Specification MAP/CV57/Is Dated 30.4.48. To be read in conjunction K1001, ignoring clauses: 5.3, 5.8, 7.2.		SEC ification TRICTED	URITY Valve UNCLASSIFTED						
Indicates a change									
TYPE OF VALVE - Tetrode CATHOLE - Indirectl ENVELOPE - Glass-uns	MARKING See K1001/4								
RATING	Note	BASE T4							
Heater Voltage (V)	12.6		See K1001/AIV/D7						
Heater Current (A)	1.75	İ	Pin	Elect	rode				
Max. Anode Voltage (kV)	11.0		1	Control	grid				
Max. Screen Voltage (kV) Max. Anode Dissipa-	1.4		2	Heater					
tion (W)	15.0		3	Screen grid					
Max. Screen Dissipa-			Heater & Cathode T.C. Anode						
tion (W)	2.5		1.00	I wrione	·				
Max. Grid Bias for cut- off (V)		TOP CAP							
Max. Peak Anode Current		See K1001/AI/D5.1							
(A)	5.0		DIMENSIONS						
Max. Peak Screen									
Current (A)	0.6		See K1001/AI/D1.			,			
OADAOTTA WOTTE (-72)		Dimension		Min.	Max.				
CAPACITANCES (pF)	44.0		_ Z B	(mm) (mm)	152	165 57			
Cae Cge	11.0								
Cag	0.5								
NOTE A:- The above ratings app as a series modulator off-on ratio of 400 t			•						
-					•				

CV57

To be performed in addition to those applicable in K1001.

<u> </u>	T	Tes		ditions			Test		Limits		No.	
	Vh	Vg1	Vg2	Va	Ig2	Ia			Min.	Max.	Tested	Note
a.	Be- tween 12V. and 15V.	- Strapped. Applied voltage raised slowly to 3.5kV. and maintained till flash- ing ceases.			A trace		SCREEN HOT FLASH PROCESS Applied anode and screen voltage to be maintained at 3.5kV. for a period of one minute without further flashing.				100%	1
р	ditto	Strapped Raised slowly to 18kV and maintain ed till flashing ceases.			•	A tazone	ANOIS NOT Frault PROCESS Applied anode voltage to be maintained at 18kV. for a period of one minute without "urther flashing.			100%	1	
c	12.6	0	0	0	0	0	Ih	(A)	1.55	1.95	100%	
đ	12.6	- Strapped. Ia + Ig 200V. 75mA. applied. ained for 30secs.					Ig	(μΑ)	-	20	100%	
е	12.6	-	200	apped. V. lied.		+ Ig2 = 5mA.	∀g1	(V)	-30	-45	100%	
f	12.6	-	See	Note 2.	-	10μΑ	Vg1	(v)	•	- 25	100%	2
g	5.25 A.C. or D.C.	0	300	apped. V. lied.	-	-	Ic	(mA)	15		100%	
h	See	K100	1/AII	I			1. (2. (6.9 15.75	11.1 26.25	1%(1) 1%(1)	

NOTES

- 1:- Tests (a) and (b) form part of the processing of the valve, and having been met during manufacture they shall not be repeated for acceptance testing. For these hot flash tests, the applied voltage shall be supplied through a circuit as in Fig. 1, page 3.
- 2. For test (f), the anode and screen grid voltages shall be derived from the network as in Fig. 2, page 3.